

# SN54S135, SN74S135 QUADRUPLE EXCLUSIVE-OR/NOR GATES

SDLS204

DECEMBER 1972—REVISED MARCH 1988

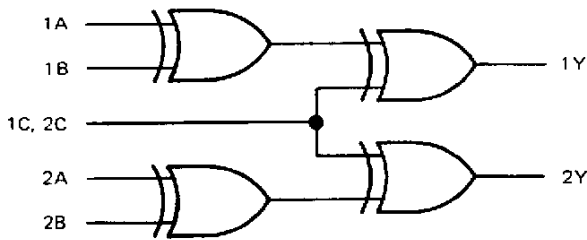
- Fully Compatible with Most TTL and TTL MSI Circuits
- Fully Schottky Clamping Reduces Delay Times . . . 8 ns Typical
- Can Operate as Exclusive-OR Gate (C Input Low) or as Exclusive-NOR Gate (C Input High)

FUNCTION TABLE

INPUTS			OUTPUT
A	B	C	Y
L	L	L	L
L	H	L	H
H	L	L	H
H	H	L	L
L	L	H	H
L	H	H	L
H	L	H	L
H	H	H	H

H = high level, L = low level

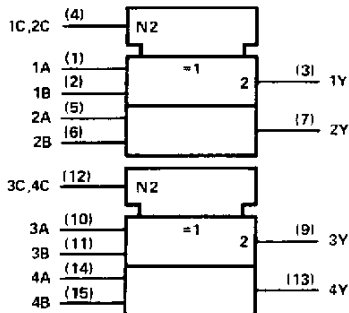
### logic diagram (one half)



### positive logic

$$Y = A \oplus B \oplus C = \overline{A}\overline{B}C + \overline{A}B\overline{C} + A\overline{B}\overline{C} + ABC$$

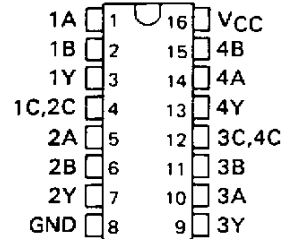
### logic symbol†



†This symbol is in accordance with ANSI/IEEE Std. 91-1984 and IEC Publication 617-12. Pin numbers are for D, J, N, and W packages.

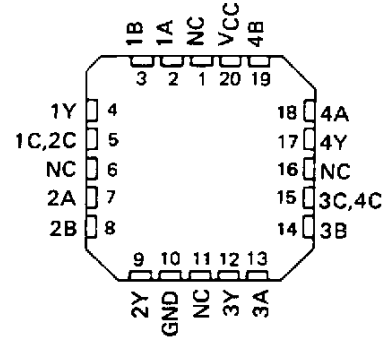
SN54S135 . . . J OR W PACKAGE  
SN74S135 . . . D OR N PACKAGE

(TOP VIEW)



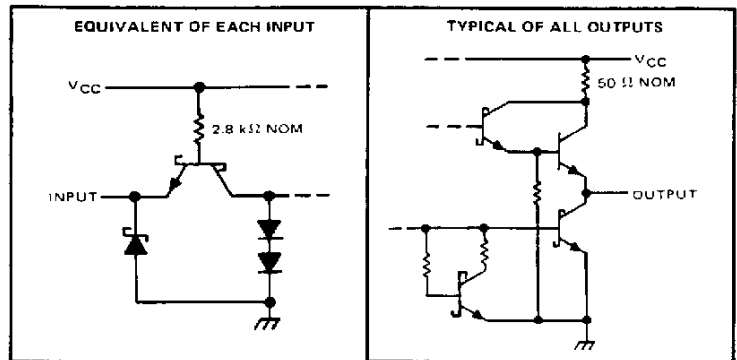
SN54S135 . . . FK PACKAGE

(TOP VIEW)



NC - No internal connection

### schematics of inputs and outputs



Resistor values shown are nominal.

PRODUCTION DATA documents contain information current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.

TEXAS  
INSTRUMENTS

POST OFFICE BOX 655012 • DALLAS, TEXAS 75265

# SN54S135, SN74S135 QUADRUPLE EXCLUSIVE-OR/NOR GATES

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, $V_{CC}$ (see Note 1)	7 V
Input voltage	5.5 V
Operating free-air temperature range: SN54S135	-55°C to 125°C
SN74S135	0°C to 70°C
Storage temperature range	-65°C to 150°C

NOTE 1: Voltage values are with respect to network ground terminal.

recommended operating conditions

	SN54S135			SN74S135			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
Supply voltage, $V_{CC}$	4.5	5	5.5	4.75	5	5.25	V
High-level output current, $I_{OH}$			-1			-1	mA
Low-level output current, $I_{OL}$			20			20	mA
Operating free-air temperature, $T_A$	-65		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS†	MIN	TYP‡	MAX	UNIT
$V_{IH}$ High-level input voltage		2			V
$V_{IL}$ Low-level input voltage				0.8	V
$V_{IK}$ Input clamp voltage	$V_{CC} = \text{MIN}, I_I = -18 \text{ mA}$			-1.2	V
$V_{OH}$ High-level output voltage	$V_{CC} = \text{MIN}, V_{IH} = 2 \text{ V},$ $V_{IL} = 0.8 \text{ V}, I_{OH} = -1 \text{ mA}$	SN54S' 2.5	3.4		V
		SN74S' 2.7	3.4		
$V_{OL}$ Low-level output voltage	$V_{CC} = \text{MIN}, V_{IH} = 2 \text{ V},$ $V_{IL} = 0.8 \text{ V}, I_{OL} = 20 \text{ mA}$			0.5	V
$I_I$ Input current at maximum input voltage	$V_{CC} = \text{MAX}, V_I = 5.5 \text{ V}$			1	mA
$I_{IH}$ High-level input current	$V_{CC} = \text{MAX}, V_I = 2.7 \text{ V}$			50	µA
$I_{IL}$ Low-level input current	$V_{CC} = \text{MAX}, V_I = 0.5 \text{ V}$			-2	mA
$I_{OS}$ Short-circuit output current§	$V_{CC} = \text{MAX}$	-40		-100	mA
$I_{CC}$ Supply current	$V_{CC} = \text{MAX},$ See Note 2		65	99	mA

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type.

‡ All typical values are at  $V_{CC} = 5 \text{ V}, T_A = 25^\circ\text{C}$ .

§ Not more than one output should be shorted at a time and duration of the short circuit should not exceed one second.

NOTE 2:  $I_{CC}$  is measured with the inputs grounded and the outputs open.

switching characteristics,  $V_{CC} = 5 \text{ V}, T_A = 25^\circ\text{C}$

PARAMETER	FROM (INPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$t_{PLH}$	A or B	B or A = L, C = L	8.5	11	13	ns
$t_{PHL}$						
$t_{PLH}$	A or B	B or A = H, C = L	8	9	12	ns
$t_{PHL}$						
$t_{PLH}$	A or B	B or A = L, C = H	10	6.5	15	ns
$t_{PHL}$						
$t_{PLH}$	A or B	B or A = H, C = H	8.5	7	12	ns
$t_{PHL}$						
$t_{PLH}$	C	A = B	8	9.5	12	ns
$t_{PHL}$						
$t_{PLH}$	C	A ≠ B	7.5	7.5	11.5	ns
$t_{PHL}$						

$C_L = 15 \text{ pF}, R_L = 280 \Omega,$   
See Note 3

NOTE 3: Load circuits and voltage waveforms are shown in Section 1.



## **IMPORTANT NOTICE**

Texas Instruments (TI) reserves the right to make changes to its products or to discontinue any semiconductor product or service without notice, and advises its customers to obtain the latest version of relevant information to verify, before placing orders, that the information being relied on is current.

TI warrants performance of its semiconductor products and related software to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

Certain applications using semiconductor products may involve potential risks of death, personal injury, or severe property or environmental damage ("Critical Applications").

**TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, INTENDED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT APPLICATIONS, DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS.**

Inclusion of TI products in such applications is understood to be fully at the risk of the customer. Use of TI products in such applications requires the written approval of an appropriate TI officer. Questions concerning potential risk applications should be directed to TI through a local SC sales office.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards should be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance, customer product design, software performance, or infringement of patents or services described herein. Nor does TI warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used.